

adapted from Microelectronic devices and circuits, Fonstad, 1994.

through the structure with a negative applied bias (i.e., $v_{AB} < 0$).

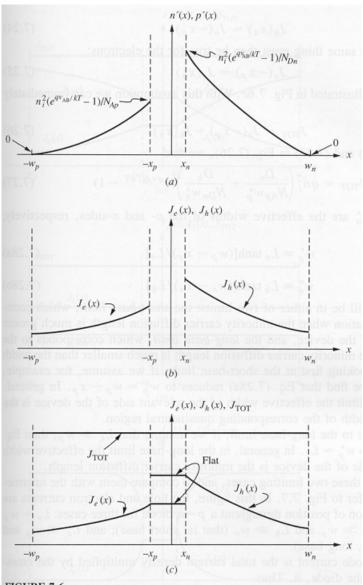


FIGURE 7.6
(a) Excess carrier populations in a forward-biased p-n junction diode; (b) the corresponding minority carrier diffusion current densities on either side of the junction; (c) the connection of the currents through the depletion region to obtain total current density.

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